


<b>Search Notes</b> 	<b>Application/Control No.</b> 10673631	<b>Applicant(s)/Patent Under Reexamination</b> HWANG, YONG SUK
	<b>Examiner</b> Lee, Siu M	<b>Art Unit</b> 2611

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	326, 150, 316, 371, 354, 373, 375, 376	12/07/2006	Siu M. Lee

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
US-PGPUB	12/07/2006	Siu M. Lee
USPAT	12/07/2006	Siu M. Lee
USOCR	12/07/2006	Siu M. Lee
EPO	12/07/2006	Siu M. Lee
JPO	12/07/2006	Siu M. Lee
Derwent	12/07/2006	Siu M. Lee
IBM_TDB	12/07/2006	Siu M. Lee
Discussed the application with Chieh Fan	12/07/2006	Siu M. Lee

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>